IN THE CLAIMS

Please amend the claims as follows:

- 1-10. (Canceled)
- 11. (Currently amended) An epitaxial growth method comprising: growing an epitaxial layer on a layered substrate which exhibits bowing so as to reduce said bowing, wherein the layered substrate has at least two layers, wherein at least two of the layers have different thermal coefficients and have the same growth temperature.
- 12. (Previously presented) The epitaxial growth method of claim 11 further comprising the step of selective etching a portion of the epitaxial layer.
- 13. (Original) The epitaxial growth method of claim 11 wherein the epitaxial layer comprises a III-V nitrides alloy and the material of the top layer of the layered substrate is selected from the group consisting of sapphire, silicon, silicon carbide, zinc oxide, gallium arsenide, gallium phosphide, indium phosphide, LiGaO₂, and LiAlO₂.
- 14. (Original) The epitaxial growth method of claim 11 wherein the epitaxial layer comprises a III-V nitrides alloy and the substrate is selected from the group consisting of sapphire on silicon, sapphire on a III-V nitrides alloy, sapphire on zinc oxide, and sapphire on silicon carbide.
 - 15-23. (Canceled)
- 24. (Previously presented) The epitaxial growth method of claim 11 further comprising the step of removing the layered substrate after growing the epitaxial layer.
- 25. (Previously presented) The epitaxial growth method of claim 24 wherein the step of removing comprises mechanical polishing.

09/904,131

26. (Previously presented) The epitaxial growth method of claim 11 wherein a process of forming said layered substrate includes a heating step, wherein said layered substrate exhibits the bowing after being cooled down from said heating step.

27. (Canceled)